

# INFORMATION DISCLOSURE CITATION

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David E. Lackey

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## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	6,092,224	7/2000	LeBlanc et al.			
	5,949,797	9/1999	Jung			
	5,838,692	11/1998	Tobin			
	5,799,021	8/1998	Gheewala			
	5,578,938	11/1996	Kazami			
	5,235,566	8/1993	Merrill			
	5,231,314	7/1993	Andrews			
	5,208,178	5/1993	Usami			
	5,369,643	11/1994	Rastgar et al.			
	6,038,691	3/2000	Nakao et al.			

## FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

		Nakao et al., LOW OVERHEAD TEST POINT INSERTION FOR SCAN-BASED BIST, ITC International Test Conference, pages 348-357.
		M. Youssef et al., Methodology for Efficiently Inserting and Condensing Test Points, IEEE Proceedings, Pages 154-160, May 1993.

EXAMINER

DATE CONSIDERED

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.